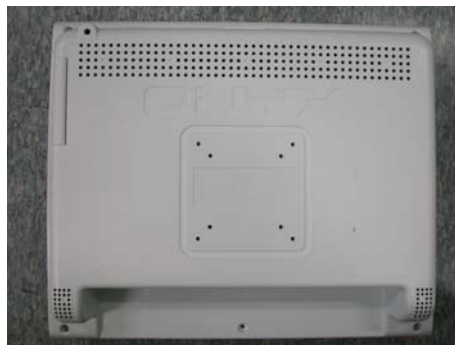


Test item list

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Num	Item	Spec
1.	Low Noise Medical Station:	Onyx-217
	1.LCD	TFT LCD.17".CPT.CLAA170EA07.4 LAMP
	2.Power Adapter	EDAC EA1050A-120
	3. Inverter	INVERTER.DC TO AC.FOR17" TFT LCD (4LAMPS).QF132V1.16
	4. A/D Board	BT-R08LDNQ REV:05
	5. USB Transfer Board	T040 REV:A02
	6. USB Board	1907YC0301 REV:A1.0
	7. CD-ROM Transfer Board	1907T04101 REV:A0.2
	8. Smart card Board	MR0103
	9. Card Reader Board	GS-2004-CR18801 V1.1
	10. CD-ROM	TEAC DV-28SL
2.	Test System	AEC-6900 (PCM-6892 B1.0 / 256MB / BIOS:0.2)



Temperature cycle test

Test Date: 01-13~16-2006

Test Product: Onyx-217

Test Site: AAEON QA Internal Lab.

Performed By: Ryan Cheng

Test Standard: Reference IEC68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:

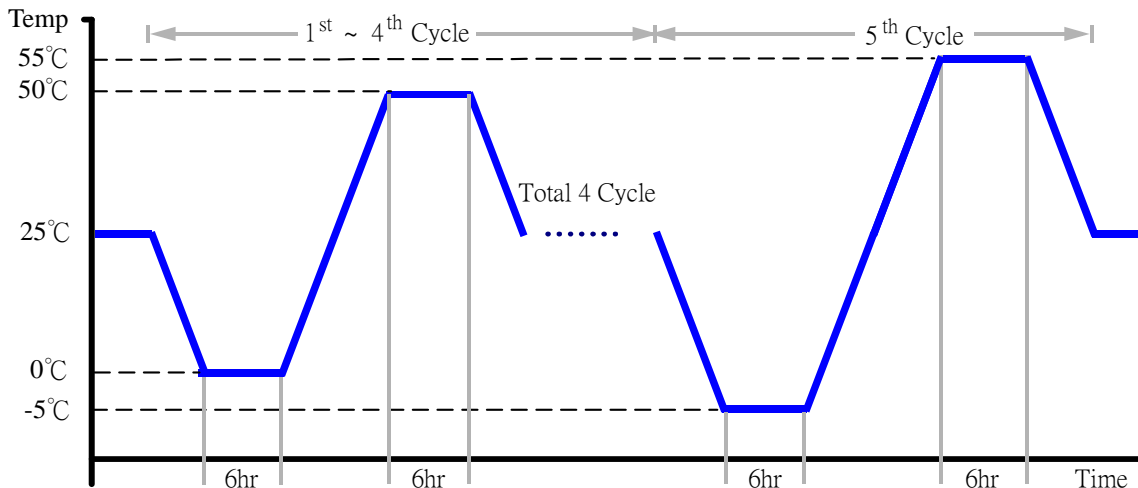
Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4L+-100
Date of Calibration: 11/21/05
Serial Number: 2582

Temperature Measurement:

20 Channel Thermal Recorder:
YOKOGAWA Inc,
Model: DA100-13-1D
Date of Calibration: 12/25/04
Serial Number: 12A323190

Test Condition:

1. Test Low Temperature: 0°C (1~4 cycle)
-5°C (5th cycle)
2. Test High Temperature: 50°C (1~4 cycle)
55°C (5th cycle)
3. Test dwell time: 6Hrs
4. Temperature slope: 2°C/min
5. Test cycle: 5 cycle
6. Test Environment Curve:



Temperature cycle test

Test O.S. / Software:

Windows 2000 / Run PassMark Burn In Test Pro 4.0

Thermal profile data:

Onyx-217

Point	Temp. Stage(°C)	Spec	55	50	25	0	-5
1. BT-R08LDNQ REV:05 - U401		100	88.9	83.9	58.9	33.9	28.9
2. BT-R08LDNQ REV:05 - U1002		100	85.4	80.4	55.4	30.4	25.4
3. BT-R08LDNQ REV:05 - U1000		100	98.3	93.3	68.3	43.3	38.3
4. BT-R08LDNQ REV:05 - AP1117 -U1004		125	73.7	68.7	43.7	18.7	13.7
5. T040 REV:A02 - L6		115	75.1	70.1	45.1	20.1	15.1
6. T040 REV:A02 - U8		115	74.9	69.9	44.9	19.9	14.9
7. T040 REV:A02 - U7		155	68.7	63.7	38.7	13.7	8.7
8. T040 REV:A02 - U10		115	67.8	62.8	37.8	12.8	7.8
9. T040 REV:A02 - U9		100	67.8	62.8	37.8	12.8	7.8
10. T040 REV:A02 - U4		105	70.8	65.8	40.8	15.8	10.8
11. T040 REV:A02 - U3		105	72.4	67.4	42.4	17.4	12.4
12. T040 REV:A02 - U5		100	70.6	65.6	40.6	15.6	10.6
13. T040 REV:A02 - U6		100	70.8	65.8	40.8	15.8	10.8
14. Inverter - Q2		150	103.7	98.7	73.7	48.7	43.7
15. Inverter - Q4		150	90.1	85.1	60.1	35.1	30.1
16. Inverter - Q6		150	84.9	79.9	54.9	29.9	24.9
17. Inverter - T2		200	82.1	77.1	52.1	27.1	22.1
18. Inverter - Q7		150	87.7	82.7	57.7	32.7	27.7
19. Inverter - Q8		150	88.5	83.5	58.5	33.5	28.5
20. Inverter - IC1		85	82.2	77.2	52.2	27.2	22.2
21. Inverter - SX14		125	84.9	79.9	54.9	29.9	24.9
22. Chamber Air Temperature		N/A	54.9	49.9	24.9	-0.1	-5.1

Note: The description in red states which temperature is over the specification of the device.

Temperature cycle test

Sample Configuration & Quantity Under Test:

Quantity: 1 (Onyx-217)

Test Result:

No problem was found during the temperature cycle test.

Test Date: 01-10~12-2006

Test Product: Onyx-217

Test Site: AAEON QA Internal Lab.

Performed By: Ryan Cheng

Test Standard: Reference IEC 68-2-2 Testing procedures
Test Bb: Dry Heat Test (Non-operation)

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.

Model: THS-D4L+-100

Date of Calibration: 11/21/05

Serial Number: 2582

Testing Item:

1. Test Temperature: 60°C
2. Test Times: 48Hrs
3. Test Software: Windows 2000 / Run PassMark Burn In Test Pro 4.0
4. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (Onyx-217)

Test Result:

No problem was found after the high temperature storage test.

Test Date: 01-06~09-2006

Test Product: Onyx-217

Test Site: AAEON QA Internal Lab.

Performed By: Ryan Cheng

Test Standard: Reference IEC 68-2-1
Testing procedures Test Ab: Cold Test (Non-operation)

Test Equipment:
Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4H+-100
Date of Calibration: 10/01/04
Serial Number: 2582

Testing Item:

1. Test Temperature: -20°C
2. Test Times: 48Hrs
3. Test Software: Windows 2000 / Run PassMark Burn In Test Pro 4.0
4. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (Onyx-217)

Test Result:

No problem was found after the low temperature storage test.

Test Date: 01-03~05-2006

Test Product: Onyx-217

Test Site: AAEON QA Internal Lab.

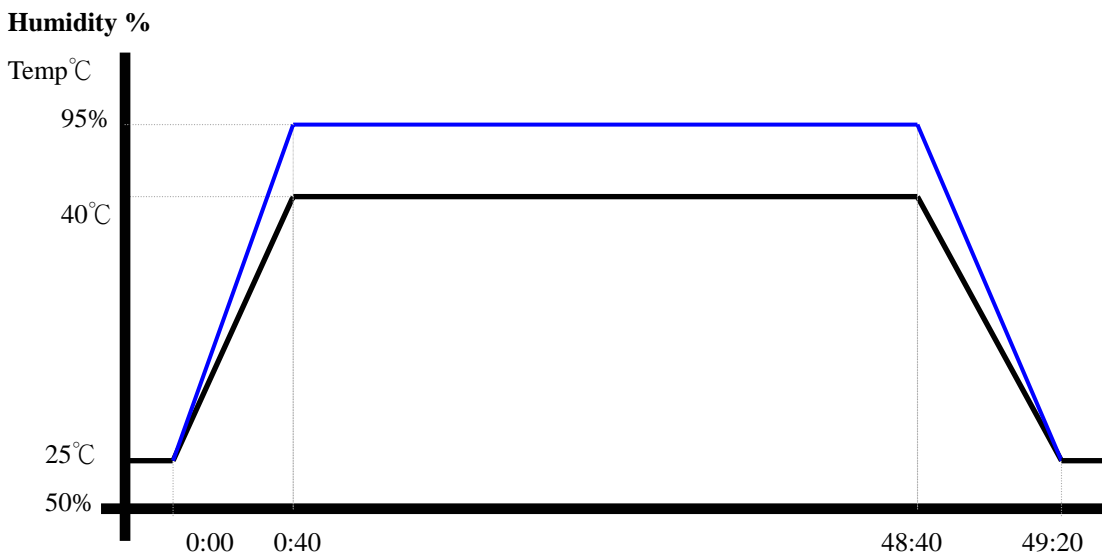
Performed By: Ryan Cheng

Test Standard: Reference IEC 68-2-3 Testing procedures
Test Ca: Damp heat, steady state (Non-operation)

Test Equipment:
Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4H+-100
Date of Calibration: 10/01/04
Serial Number: 2582

Testing Item:

1. Test Temperature: 40°C
2. Test Humidity: 95%RH
3. Test Times: 48Hrs
4. Test Software: Windows 2000 / Run PassMark Burn In Test Pro 4.0
5. Test Environment Curve:



Sample Configuration & Quantity Under Test:
Quantity: 1 (Onyx-217)

Test Result:
No problem was found after the humidity test.

Test Date: 01-02~03-2006

Test Product: Onyx-217

Test Site: AAEON QA Internal Lab.

Performed By: Ryan Cheng

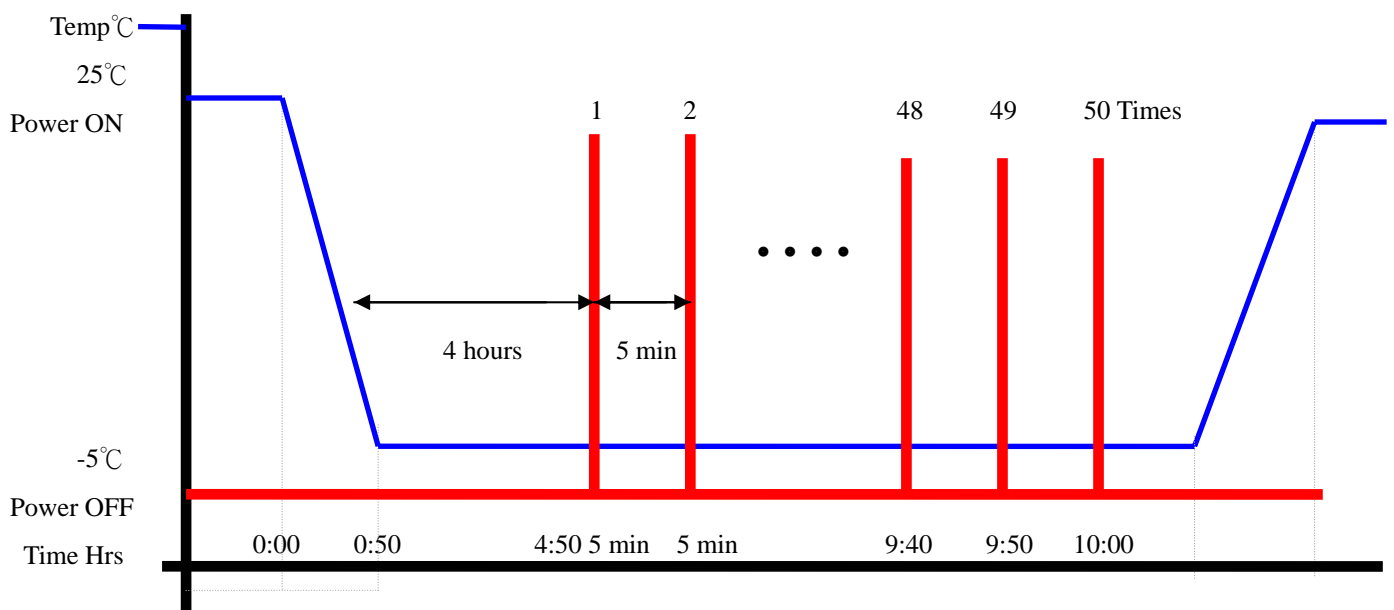
Test Standard: Reference IEC 68-2-1 Testing procedures
Test Ab: Cold Test

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D4H+-100
Date of Calibration: 10/01/04
Serial Number: 2582

Test Condition:

1. Test Temperature: -5°C
2. Test Times: 5 Hours or 50 times of ON/OFF
 - (1) Power off for 4 hours before 1'st power on. Then once complete boot, power off immediately.
 - (2) After 5 min later power on again and wait until booting is completed.
 - (3) Repeat (2) for around 4:50
 - (4) Power off then wait for 5 min before final power on operation.
3. Number of test: 50 times
4. Test Software: Windows 2000
5. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (Onyx-217)

Test Result:

No problem was found during the cold start test.